PCN Num	ber:	20240905000.1		PCN Date:	September 05, 2024		
Title: Qualification of UMC-F12 as additional Fab site for select LBC9 devices							
Custome	Contact:	Change Management Team		Dept:	Quality Services		
Proposed 1 st Ship Date:		December 04, 2024	Sample request accepted until		October 05, 2024*		
*Sample requests received after October 05, 2024 will not be supported.							

Change Type:

Assembly Site	Design		Wafer Bump Material
Assembly Process	Data Sheet		Wafer Bump Process
Assembly Materials	Part number change	\boxtimes	Wafer Fab Site
Mechanical Specification	Test Site		Wafer Fab Material
Packing/Shipping/Labeling	Test Process		Wafer Fab Process

PCN Details

Description of Change:

Texas Instruments is pleased to announce the addition of UMC-F12 as an additional Wafer Fab site option for the products listed in the "Product Affected" section of this document.

	Current Fab Site)	Additional Fab Site			
Current Fab Process Site		Wafer Diameter	Additional Fab Site	Process	S Wafer Diameter	
RFAB	LBC9	300 mm	UMC-F12	LBC9	300 mm	

Qual details are provided in the Qual Data Section.

Reason for Change:

Continuity of Supply

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Changes to product identification resulting from this PCN:

Fab Site

Information:

Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City	
RFAB	RFB	USA	Richardson	
UMC-F12	F12	TWN	Tainan	

Sample product shipping label (not actual product label):





(1P) SN74LS07NSR (a) 2000 (D) 0336 (31T)LOT: 3959047MLA (4W) TKY(1T) 7523483S12

(2P) REV: (2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MYS

Product Affected:

BQ25672RQMR	BQ25792RQMR	BQ25798RQMR
TPS25751DREFR	TPS25751SRSMR	

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	#	Test Name	Condition	Duration	Qual Device: <u>BQ25792RQMR</u>	QBS Reference: <u>BQ25792RQMR</u>
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	3/231/0
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	-	3/231/0
TC	A4	Temperature Cycle	-55C/125C	700 Cycles	1/77/0	3/231/0
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	3/231/0
HTOL	B1	Life Test	125C	1000 Hours	1/77/0	3/231/0
PD	C4	Physical Dimensions	(per mechanical drawing)	-	-	3/15/0
ESD	E2	ESD CDM	-	1500 Volts	1/3/0	1/3/0
ESD	E2	ESD HBM	-	4000 Volts	1/3/0	1/3/0
LU	E4	Latch-Up	Per JESD78	-	1/6/0	1/3/0
CHAR	E5	Electrical Characterization	Min, Typ, Max Temp	-	-	1/30/0
FTY	E6	Final Test Yield	-	-	1/1/0	-

- QBS: Qual By Similarity
- Qual Device BQ25792RQMR is qualified at MSL2 260C
- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

TI Qualification ID: R-CHG-2108-035

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	#	Test Name	Condition	Duration	Qual Device: BQ25798RQMR	QBS Package/Process/Product Reference: <u>BQ25792RQMR</u>	QBS Package/Process/Product Reference: <u>BQ25792RQMR</u>	QBS Process Reference: CD3253DB0YCHR
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	3/231/0	-
UHAST	A3	Unbiased HAST	130C/85%RH	96 Hours	-	-	3/231/0	-
TC	A4	Temperature Cycle	-55C/125C	700 Cycles	-	1/77/0	3/231/0	-
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	-	3/231/0	-
HTOL	B1	Life Test	125C	1000 Hours	-	1/77/0	3/231/0	3/231/0
ELFR	B2	ELFR	125C	48 Hours				3/3000/0
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes); PB Solder;	-	-	-	1/22/0	-

Туре	#	Test Name	Condition	Duration	Qual Device: BQ25798RQMR	QBS Package/Process/Product Reference: <u>BQ25792RQMR</u>	QBS Package/Process/Product Reference: <u>BQ25792RQMR</u>	QBS Process Reference: CD3253DB0YCHR
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes); PB- Free Solder;	-	-	-	3/66/0	-
PD	C4	Physical Dimensions	(per mechanical drawing)	-	-	-	3/15/0	-
ESD	E2	ESD CDM	-	250 Volts	1/3/0	-	-	-
ESD	E2	ESD HBM	-	1000 Volts	1/3/0	-	-	-
LU	E4	Latch-Up	Per JESD78	-	1/6/0	-	-	-
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	-	-	-
FTY	E6	Final Test Yield	-	-	1/PASS	-	-	-

- · QBS: Qual By Similarity
- Qual Device BQ25798RQMR is qualified at MSL2 260C
- · Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

TI Qualification ID: R-CHG-2108-003

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре		Test Name	Condition	Duration	Qual Device: TPS65992SBGRSMR	Qual Device: TPS65992SBGRSMR	Qual Device: TPS65992EBGRSMR	Qual Device: TPS65992EBGRSMR	Qual Device: TPS65992DBGREFR	Qual Device: TPS65992DBGREFR	QBS Reference: PTPS65992SA0CRSMR	QBS Reference: PTPS65992SADRSMR
HAST	A2	Biased HAST	110C/85%RH	264 Hours	-		-		-		1/77/0	
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	-	-	-	-	-	-
UHAST	А3	Autoclave	121C/15psig	96 Hours	-	-	-	-	-	-	1/77/0	-
UHAST	А3	Unbiased HAST	130C/85%RH	96 Hours	-	-	-	-	-	-	-	
TC	A4	Temperature Cycle	-55C/125C	700 Cycles						-		
TC	A4	Temperature Cycle	-65C/150C	500 Cycles							1/77/0	
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	-	-	-	-	-	1/77/0	-
HTSL	A6	High Temperature Storage Life	175C	420 Hours	-	-	-	-	-	-	-	-
HTOL	B1	Life Test	125C	1000 Hours	-	-	-	-	-	-	2/154/0	1/77/0
ELFR	B2	Early Life Failure Rate	125C	48 Hours	-	-	-	-	-	-	2/1600/0	1/800/0
SD	С3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes); PB Solder;		-		-	-	-	-	-	-
SD	СЗ	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes); PB- Free Solder;	-	-	-	-	-	-	-	-	-
PD	C4	Physical Dimensions	(per mechanical drawing)	-	-	-	-	-	-	-	-	-
Туре	#	Test Name	Condition	Duration	Qual Device: IPS65992SBGRSMR	Qual Device: IPS65992SBGRSMR	Qual Device: TPS65992EBGRSMR	Qual Device: TPS65992EBGRSMR	Qual Device: IPS65992DBGREFR	Qual Device: IPS65992DBGREFR	QBS Reference: PTPS65992SA0CRSMR	QBS Reference: PTPS65992SADRSMR
ESD	E2	ESD CDM		1000 Volts				-		-	-	
ESD	E2	ESD CDM		1500 Volts	-	-	-	-	-	-	-	1/3/0
ESD	E2	ESD HBM		1500 Volts							-	1/3/0
ESD	E2	ESD HBM		2500 Volts		-	-			-		
ESD	E2	ESD HBM		4000 Volts						-		
LU	E4	Latch-Up	Per JESD78	-	-	-	-	-	-	-	-	1/3/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	1/30/0	-	-	-	-	-	-	-
FTY	E6	Final Test Yield	-		1/1/0	1/1/0	1/1/0	1/1/0	1/1/0	1/1/0		-

- · QBS: Qual By Similarity
- . Qual Device TPS65992SBGRSMR is qualified at MSL2 260C
- . Qual Device TPS65992SBGRSMR is qualified at MSL2 260C
- . Qual Device TPS65992EBGRSMR is qualified at MSL2 260C
- · Qual Device TPS65992EBGRSMR is qualified at MSL2 260C
- Qual Device TPS65992DBGREFR is qualified at MSL2 260C
- Qual Device TPS65992DBGREFR is qualified at MSL2 260C
- . Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours
- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Ouality and Environmental data is available at TI's external Web site: http://www.ti.com/

TI Qualification ID: R-CHG-2301-010

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